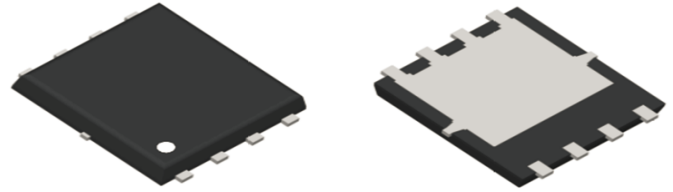


Description

The XPX130N15RD uses advanced technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.



General Features

$V_{DS} = 150V$ $I_D = 120A$

$R_{DS(ON)} < 8.5m\Omega$ @ $V_{GS}=10V$

Application

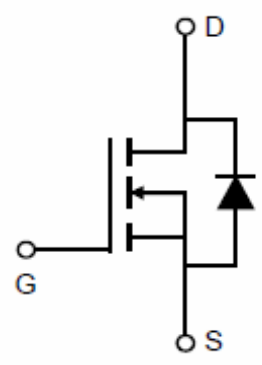
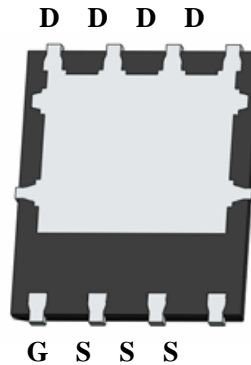
DC/DC

LED

Power Management Switches

Converter

Backlighting



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
XPX130N15RD	PDFN5*6-8L	XPX130N15RDXXX YYYY	5000

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	150	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V$	130	A
$I_D @ T_C=100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V$	80	A
IDM	Pulsed Drain Current	360	A
EAS	Single Pulse Avalanche Energy	406	mJ
IAS	Avalanche Current	43	A
$P_D @ T_C=25^\circ\text{C}$	Total Power Dissipation ⁴	160	W
TSTG	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient	25	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case	0.75	$^\circ\text{C/W}$

Electrical Characteristics (T_C=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA	150	172	-	V
IGSS	Gate-body Leakage Current	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
IDSS@T _J =25°C	Zero Gate Voltage Drain Current	V _{DS} = 150V, V _{GS} = 0V			1	μA
IDSS@T _J =100°C					100	
VGS(th)	Gate-Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2	3	4	V
RDS(on)	Drain-Source On-Resistance ⁴	V _{GS} = 10V, I _D = 20A	-	8.5	12	mΩ
gfs	Forward Transconductance ⁴	V _{DS} = 10V, I _D = 20A	-	69	-	S
Ciss	Input Capacitance	V _{DS} = 75V, V _{GS} = 0V, f = 1MHz	-	3306	-	pF
Coss	Output Capacitance		-	263	-	
Crss	Reverse Transfer Capacitance		-	9.4	-	
R _g	Gate Resistance	f = 1MHz	-	3.1	-	Ω
Q _g	Total Gate Charge	V _{GS} = 10V, V _{DS} = 75V, I _D = 20A	-	45	-	nC
Q _{gs}	Gate-Source Charge		-	15	-	
Q _{gd}	Gate-Drain Charge		-	8.5	-	
td(on)	Turn-On Delay Time	V _{GS} = 10V, V _{DD} = 75V, R _G = 3Ω, I _D = 20A	-	16	-	ns
t _r	Rise Time		-	12	-	
td(off)	Turn-Off Delay Time		-	30	-	
t _f	Fall Time		-	18	-	
trr	Body Diode Reverse Recovery Time	I _F = 20A, di/dt = 100A/μs	-	76	-	ns
Q _{rr}	Body Diode Reverse Recovery Charge		-	182	-	nC
VSD	Diode Forward Voltage ⁴	I _F = 20A, V _{GS} = 0V	-	-	1.2	V
IS	Continuous Source Current	T _C = 25°C	-	-	75	A

Notes:

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、 The EAS data shows Max. rating . The test condition is V_{DD}=50V, V_{GS}=10V, L=0.5mH, I_{AS}=43A
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

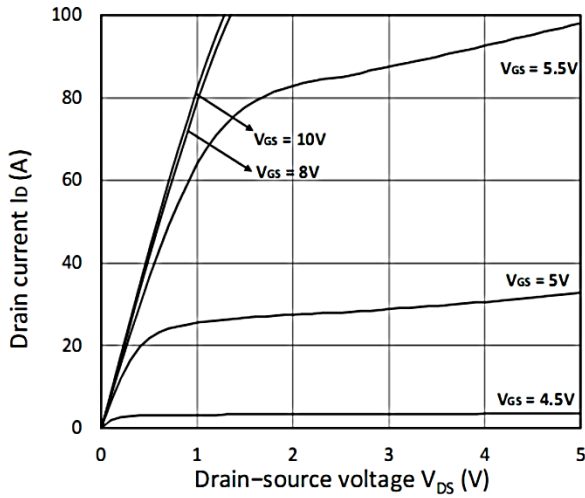


Figure 1. Output Characteristics

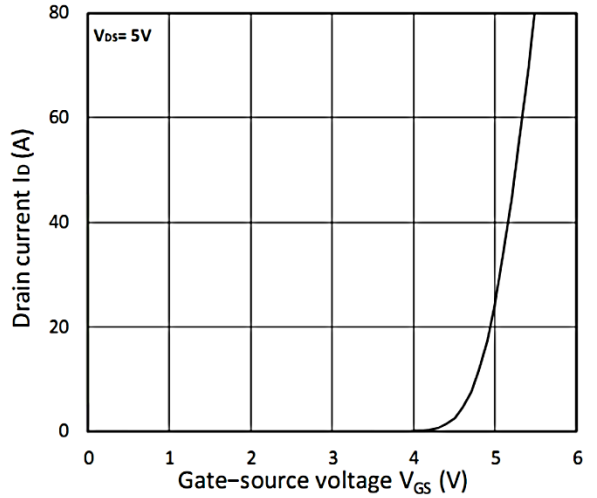


Figure 2. Transfer Characteristics

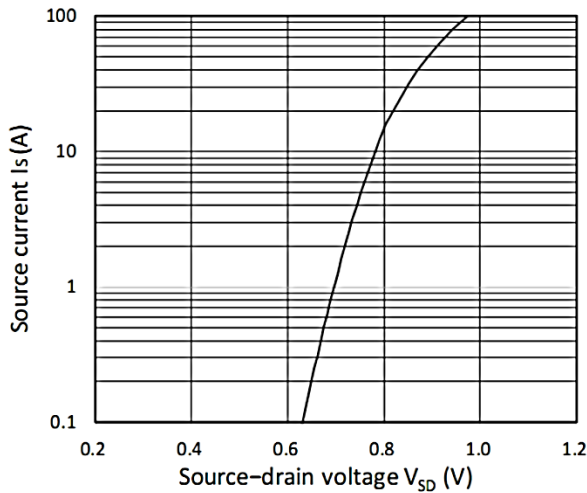


Figure 3. Forward Characteristics of Reverse

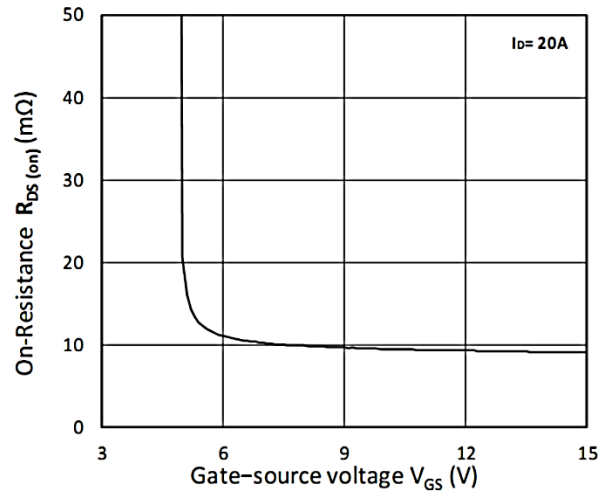


Figure 4. RDS(ON) vs. VGS

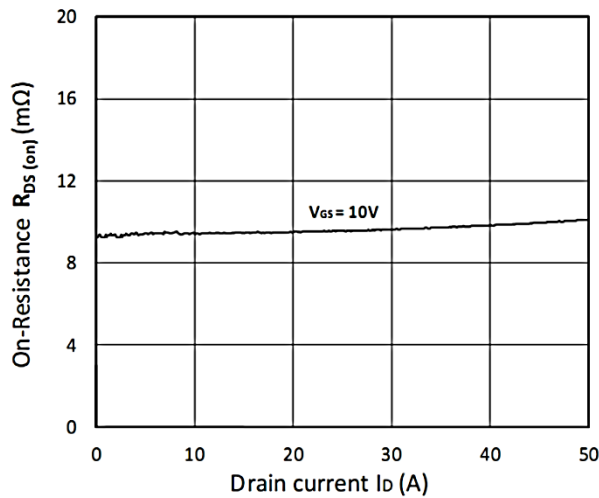


Figure 5. RDS(ON) vs. ID

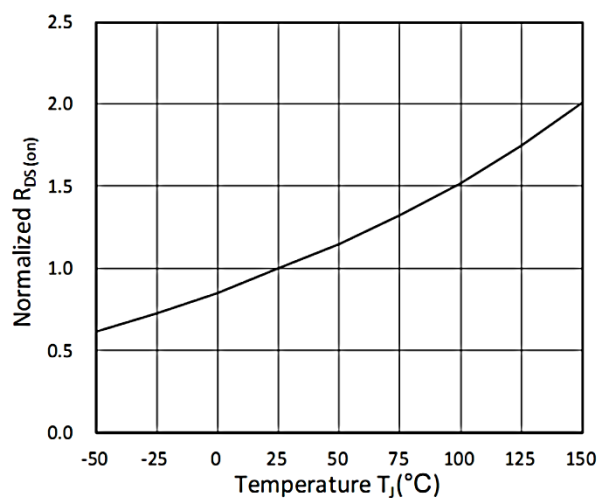


Figure 6. Normalized RDS(on) vs. Temperature

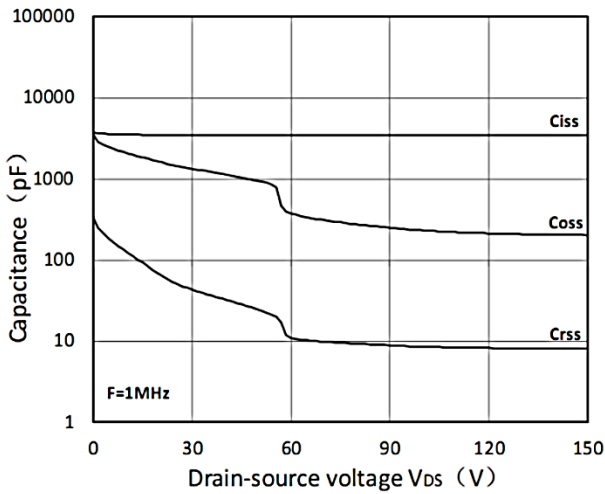


Figure 7. Capacitance Characteristics

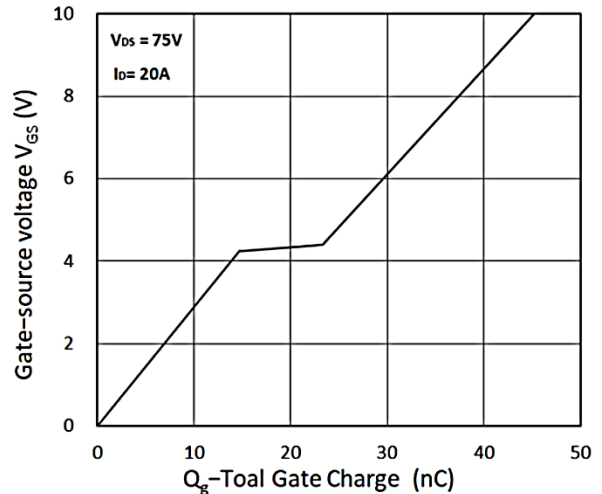


Figure 8. Gate Charge Characteristics

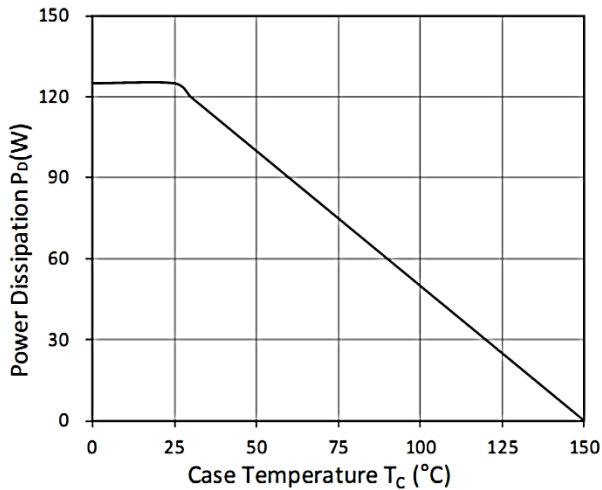


Figure 9. Power Dissipation

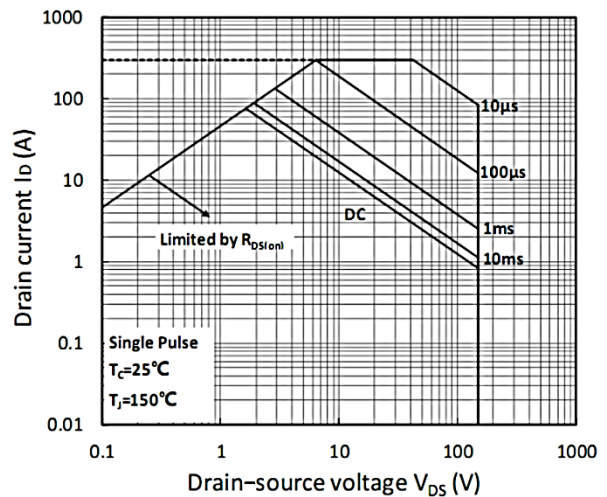


Figure 10. Safe Operating Area

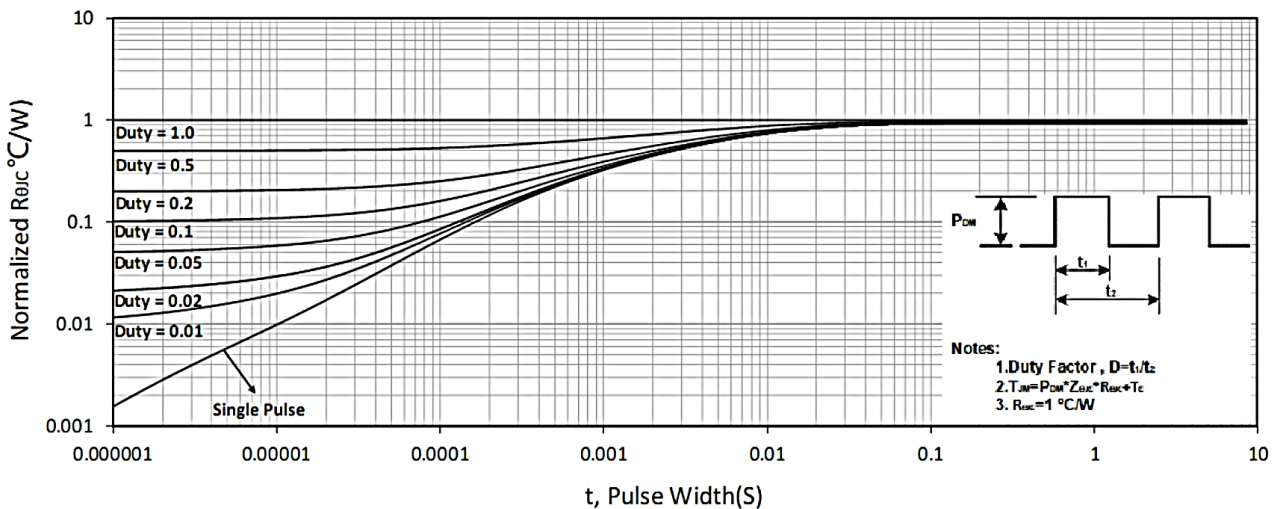
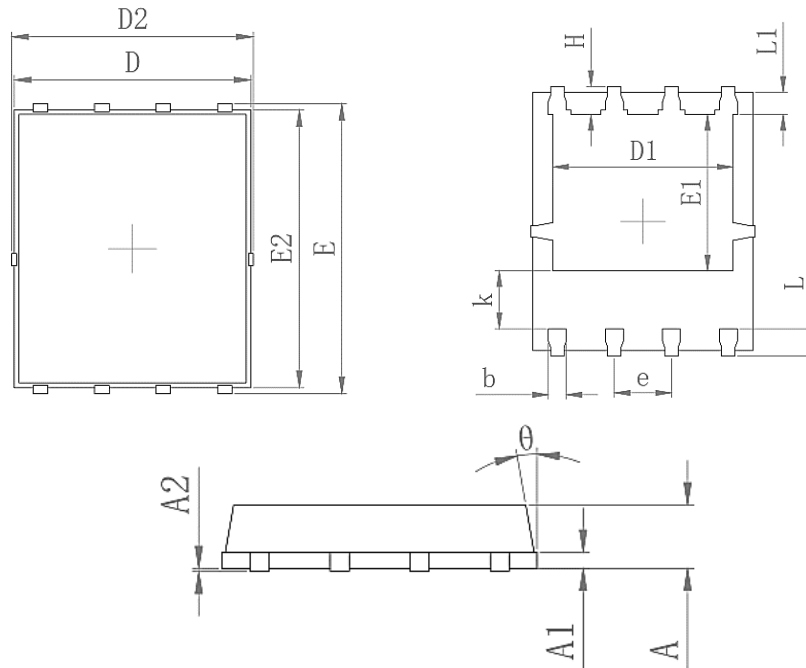


Figure 11. Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-PDFN5X6-8L-XZT Single


Symbol	Common	
	mm	
	Mim	Max
A	0.90	1.10
A1	0.254 REF	
A2	0-0.05	
D	4.824	4.976
D1	3.910	4.110
D2	4.944	5.076
E	5.924	6.076
E1	3.375	3.575
E2	5.674	5.826
b	0.350	0.450
e	1.270	
L	0.534	0.686
L1	0.424	0.576
K	1.190	1.390
H	0.549	0.701
Φ	8°	12°

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245°C ±5°C	5sec ±1sec
Pb-Free device	260°C +0/-5°C	5sec ±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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